

MS/RF PCM/PROCESS CHECKLIST SUB-WORKING GROUP MINUTES

Date: February 17, 2010

Location: Teleconference

Time: 10:00am (Pacific)

Participants:

Chelsea Boone – GSA
David Schwan – RF Micro Devices (RFMD)
Steffen Richter – X-FAB
Ehrenfried Seebacher – austriamicrosystems AG
Li Ling – Intel
Paul Hurwitz – Jazz Semiconductor

Meeting Purpose:

To make a decision on a measurement definition for each parameter description in the parameter list spreadsheet. We will not cover all parameter descriptions in one meeting. This will be an on-going process.

End Result/Conclusions:

- Per the working group's feedback, definitions were selected for various parameter descriptions. To view the definitions selected, please see Version 4 of the PCM parameter list at http://www.gsaglobal.org/ams/index_wg.aspx?tab=3 (under Resources).
- Next Meeting: We will again continue to revise Version 4 and select the appropriate measurement definitions for parameter descriptions. **March 17, 2010, 10:00am (Pacific)**